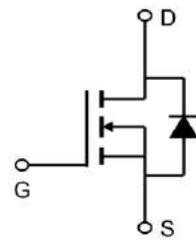


## 500V N-Channel Enhancement Mode MOSFE

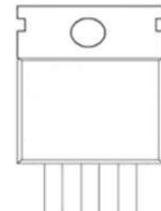
### General Description

5N50 use advanced VD MOST technology to provide low RDS(ON), low gate charge, fast switching. This device is specially designed to get better ruggedness and suitable to use in



### Features

- High EAS
- xtremely low switching loss
- Excellent stability and uniformity or Invertors



### Applications

- Consumer electronic power supply Motor control
- Synchronous-rectification Isolated AC
- Synchronous-rectification applications

### General Features

$V_{DS} = 500V$   $I_D = 5A$

$R_{DS(ON)} < 1.2\Omega$  @  $V_{GS}=10V$



### Absolute Maximum Ratings ( $T_C=25^\circ C$ unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-Source Voltage ( $V_{GS} = 0V$ )	$V_{DSS}$	500	V
Continuous Drain Current	$I_D$	5	A
Pulsed Drain Current (note1)	$I_{DM}$	28	A
Gate-Source Voltage	$V_{GSS}$	$\pm 30$	V
Single Pulse Avalanche Energy (note2)	$E_{AS}$	176	mJ
Avalanche Current (note1)	$I_{AR}$	4.2	A
Repetitive Avalanche Energy (note1)	$E_{AR}$	35	mJ
Power Dissipation ( $T_c = 25^\circ C$ )	$P_D$	83	W
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	-55~+150	°C
Thermal Resistance, Junction-to-Case	$R_{thJC}$	2.3	°C/W
Thermal Resistance, Junction-to-Ambient	$R_{thJA}$	62.5	

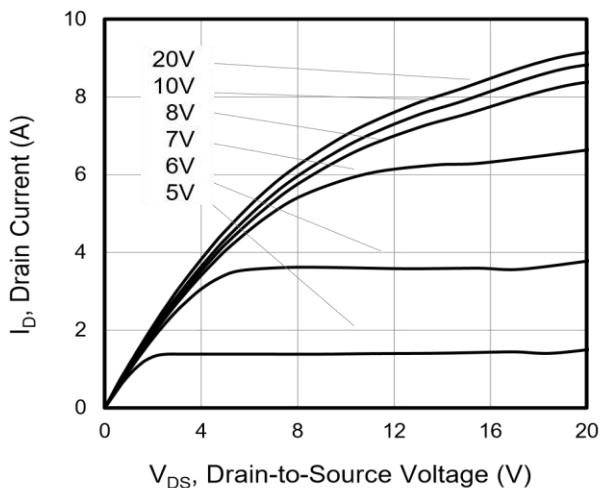
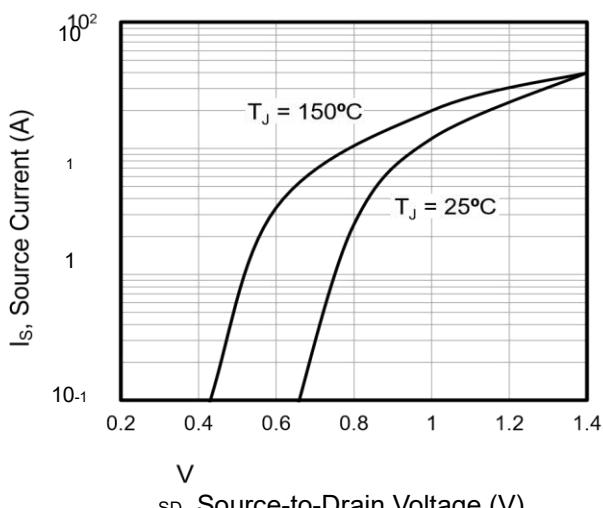
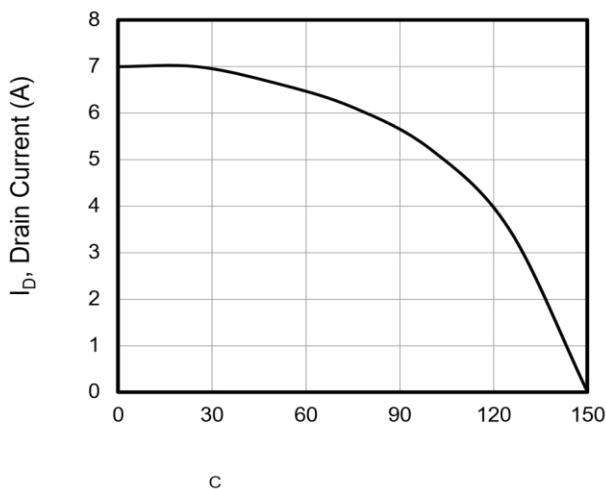
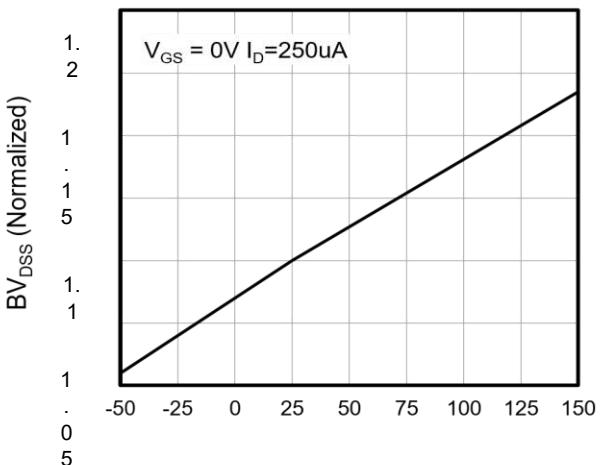
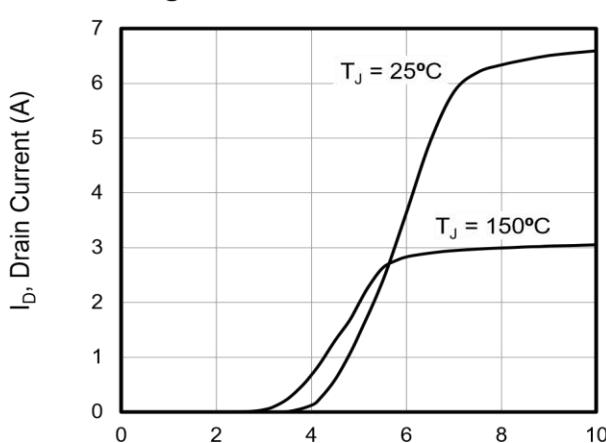
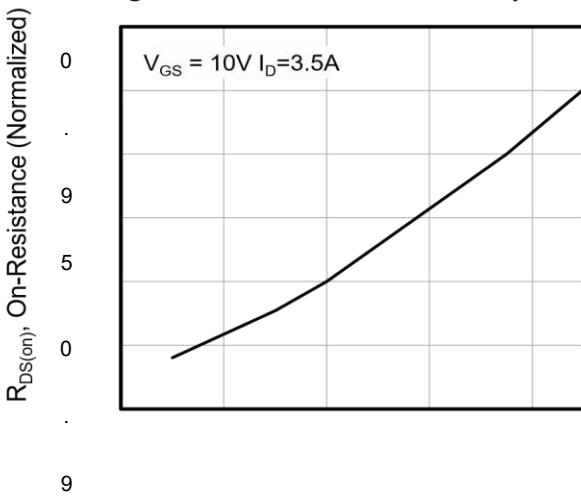
**500V N-Channel Enhancement Mode MOSFE**
**Electrical Characteristics (T<sub>C</sub>=25°C unless otherwise specified)**

Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	500	--	--	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 500V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 25°C	--	--	1	μA
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ±30V	--	--	±100	nA
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	3.0	--	4.0	V
Drain-Source On-Resistance (Note3)	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 3.5A	--	1	1.2	Ω
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 25V, f = 1.0MHz	--	700	--	pF
Output Capacitance	C <sub>oss</sub>		--	94	--	
Reverse Transfer Capacitance	C <sub>rss</sub>		--	12	--	
Total Gate Charge	Q <sub>g</sub>	V <sub>DD</sub> = 400V, I <sub>D</sub> = 7A, V <sub>GS</sub> = 10V	--	19	--	nC
Gate-Source Charge	Q <sub>gs</sub>		--	3.7	--	
Gate-Drain Charge	Q <sub>gd</sub>		--	11	--	
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 250V, I <sub>D</sub> = 7A, R <sub>G</sub> = 25Ω	--	13	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	20	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	76	--	
Turn-off Fall Time	t <sub>f</sub>		--	40	--	
Continuous Body Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C	--	--	7.0	A
Pulsed Diode Forward Current	I <sub>SM</sub>		--	--	28	
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25°C, I <sub>SD</sub> = 7A, V <sub>GS</sub> = 0V	--	--	1.4	V
Reverse Recovery Time	t <sub>rr</sub>	V <sub>GS</sub> = 0V, I <sub>S</sub> = 7A, dI <sub>F</sub> /dt = 100A /μs	--	260	--	ns
Reverse Recovery Charge	Q <sub>rr</sub>		--	3.8	--	μC

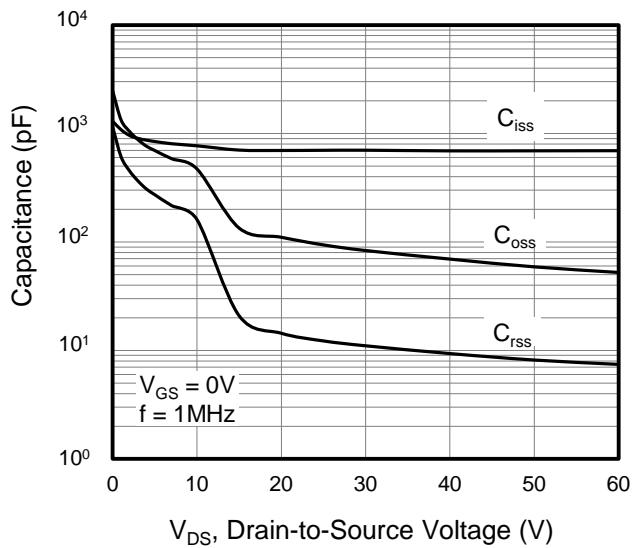
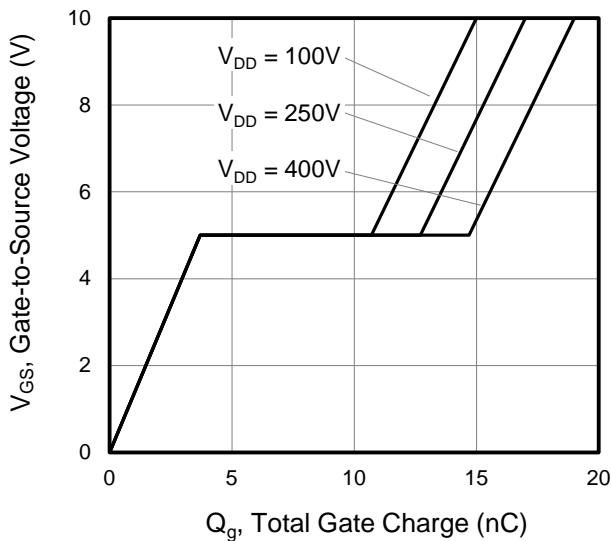
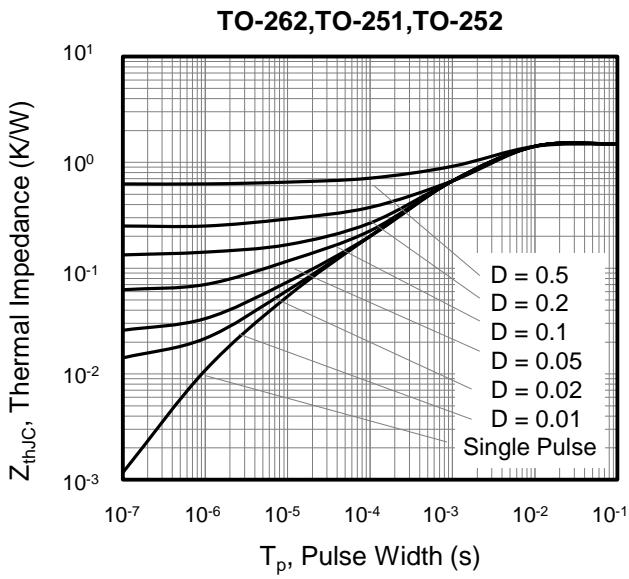
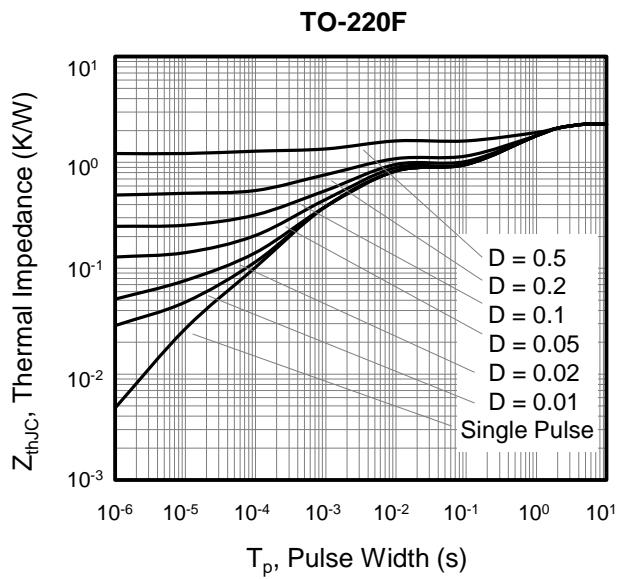
**Notes**

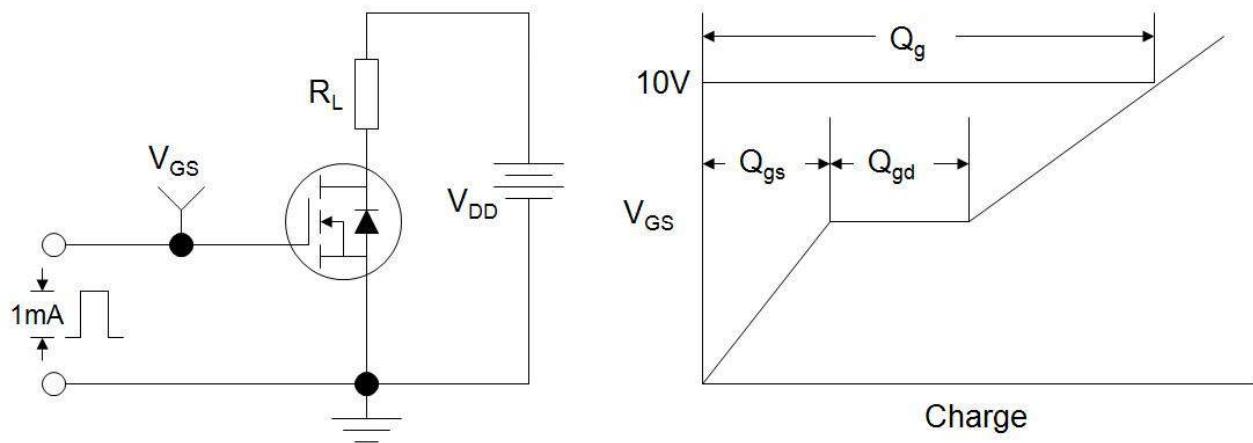
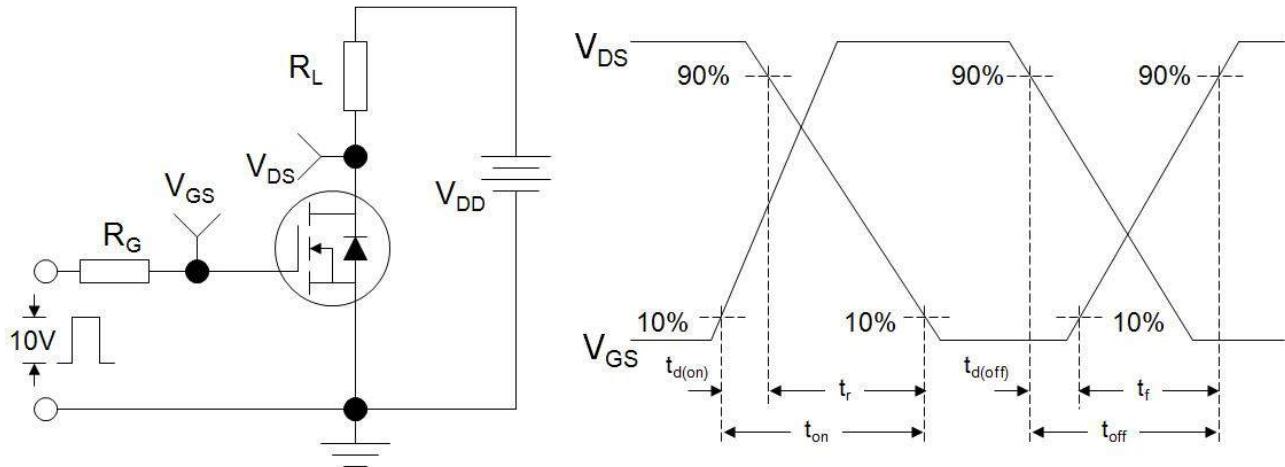
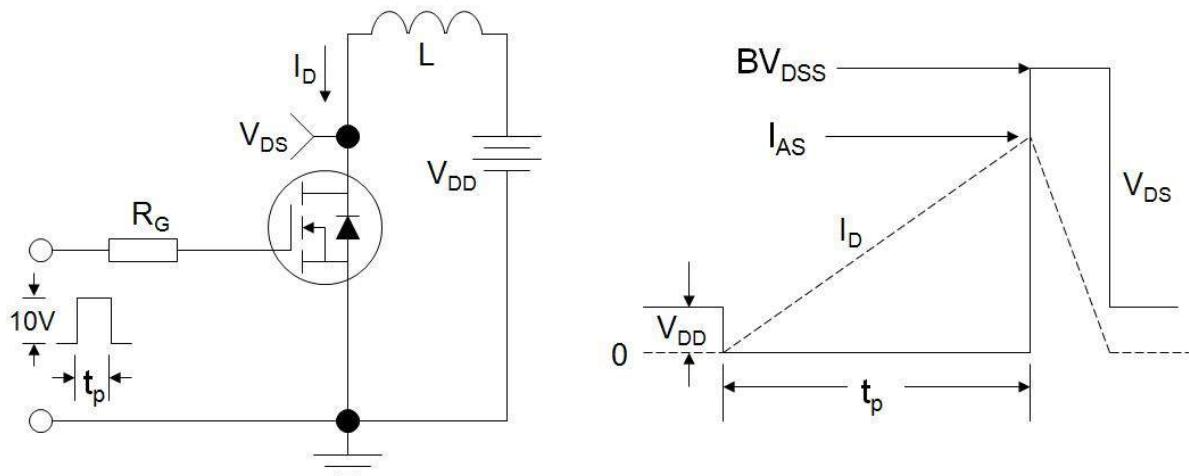
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. I<sub>AS</sub> = 4.2A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25 °C
3. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%

**500V N-Channel Enhancement Mode MOSFE**
**Typical Characteristics**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

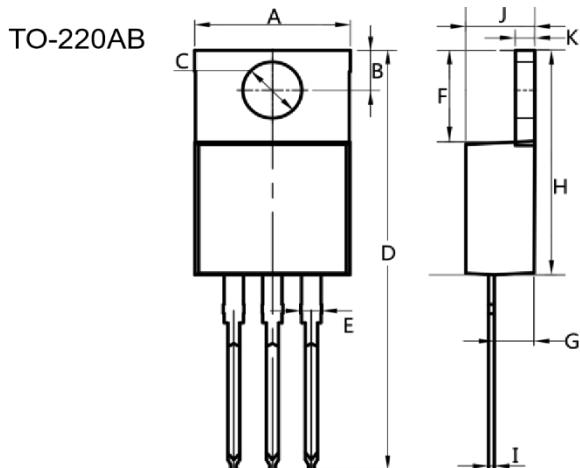
**Figure 1. Output Characteristics ( $T_J = 25^\circ\text{C}$ )**

**Figure 2. Body Diode Forward Voltage**

**Figure 3. Drain Current vs. Temperature**

**Figure 4. BV<sub>DSS</sub> Variation vs. Temperature**

**Figure 5. Transfer Characteristics**

**Figure 6. On-Resistance vs. Temperature**

 $T_c$ , Case Temperature (A)

 $T_c$ , Case Temperature (°C)

**500V N-Channel Enhancement Mode MOSFE**
**Figure 7. Capacitance**

**Figure 8. Gate Charge**

**Figure 9. Transient Thermal Impedance**

**Figure 10. Transient Thermal Impedance**


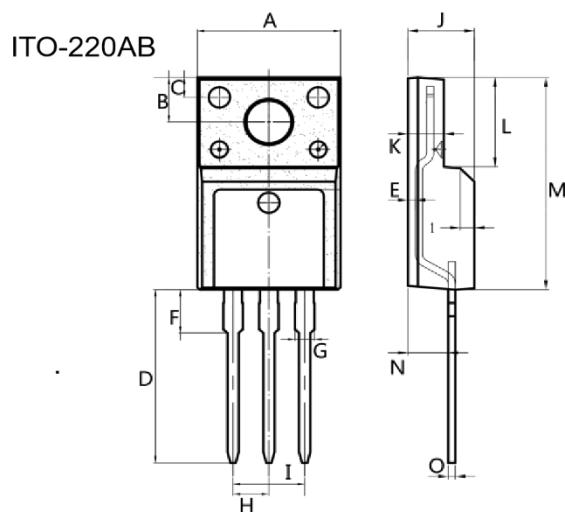
**500V N-Channel Enhancement Mode MOSFE**

**Figure B: Resistive Switching Test Circuit and Waveform**

**Figure C: Unclamped Inductive Switching Test Circuit and Waveform**


**500V N-Channel Enhancement Mode MOSFE  
Package Mechanical Data TO-220F**



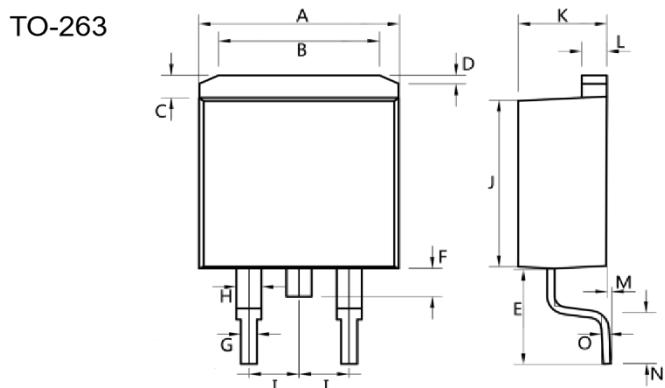
Dim.	Min.	Max.
A	10.0	10.4
B	2.5	3.0
C	3.5	4.0
D	28.0	30.0
E	1.1	1.5
F	6.2	6.6
G	2.9	3.3
H	15.0	16.0
I	0.35	0.45
J	4.3	4.7
K	1.2	1.4

All Dimensions in millimeter



Dim.	Min.	Max.
A	9.9	10.3
B	2.9	3.5
C	1.15	1.45
D	12.75	13.25
E	0.55	0.75
F	3.1	3.5
G	1.25	1.45
H	Typ 2.54	
I	Typ 5.08	
J	4.55	4.75
K	2.4	2.7
L	6.35	6.75
M	15.0	16.0
N	2.75	3.15
O	0.45	0.60

All Dimensions in millimeter



Dim.	Min.	Max.
A	10.0	10.5
B	7.25	7.75
C	1.3	1.5
D	0.55	0.75
E	5.0	6.0
F	1.4	1.6
G	0.75	0.95
H	1.15	1.35
I	Typ 2.54	
J	8.4	8.6
K	4.4	4.6
L	1.25	1.45
M	0.02	0.1
N	2.4	2.8
O	0.35	0.45

All Dimensions in millimeter